

REMARKS

Claims 1-30 are pending in the case.

It is the belief of the Applicants that the claims of the present invention are directed to a common subject matter and the search and examination of the entire application can be made by the Examiner without serious burden.

Claims 16-30 (Group I) and claims 1-15 (Group II) relate to a method for evaluating reliability of a semiconductor chip and a semiconductor device, which includes features employed for evaluating the reliability of the chip. It is respectfully submitted that serious burden would not be placed on the Examiner to search the common subject and examine both Group I and Group II claims together, obviating the need for restriction. Both sets of claims are related to a common theme and include similar elements. The Examiner is respectfully requested to reconsider the restriction requirement and examine both groups of claims together.

It is recognized that in order for this paper to be responsive to the Office Action, an election must be made. In the Office Action of June 29, 2004, restriction has been required to one of the following two groups of claims:

(I) Claims 16-30; and

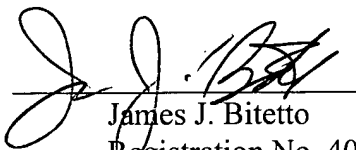
(II) Claims 1-15.

Accordingly, claims of Group (II) are elected for examination at this time with traverse. Applicant reserves the right to pursue Group (I) claims (16-30) by way of a separate divisional application.

In view of the foregoing remarks, Applicants respectfully request reconsideration of the restriction requirement. Early and favorable action of the case is respectfully requested.

Respectfully submitted,

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